S	earcn	notes	

1	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/646,631	PASQUALE ET AL.
	Examiner	Art Unit

Nicholas T. La

2617

	SEARCHED		
Class	Subclass	Date	Examiner
455	566	8/22/2006	NL
Updated	search		
			11

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SEAR)		
	DATE	EXMR
Fext search with subclasses	8/22/2006	NL
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